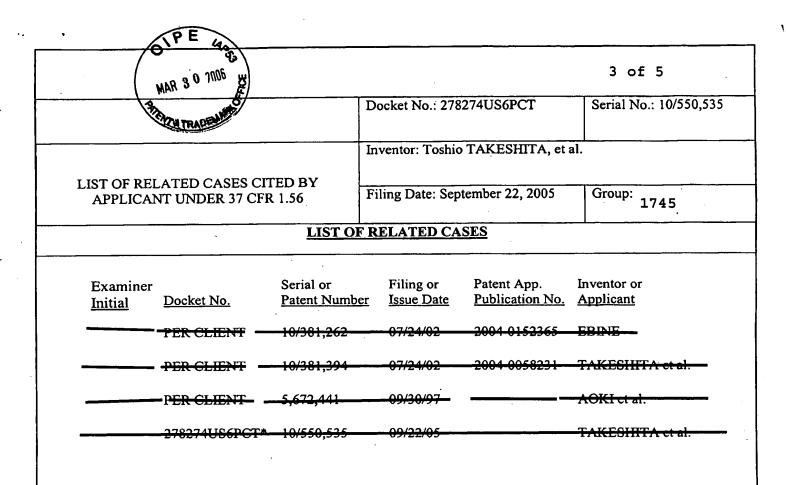
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SHEET 1 OF 5

Form PTO 1449	9 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		New U.S.P.C.T Application			
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LIST OF	REFER	ENCES CITED BY AF	PLICANT	Toshio TAKESHITA, et al.		000110			
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				U.S. PATENT DOCUMENTS					
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SK	AO	2003-036828	02/07/03	JP				NO	
SK	AP	62-140669	09/04/87	JP				NO	
SK	AQ	07-312212	11/28/95	JP		<u> </u>		NO	
SK	AR	06-104017	04/15/94	JP (equivalent of US5602454)				NO	
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				278274US6PCT	10/550,535			
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				U.S. PATENT DOCUMENTS		<u> </u>		
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DAT	
SK	AA	2004-0152365	08/05/04	EBINE				
SK	AB	2004-0058231	03/25/04	TAKESHITA et al.				
SK	AC	5,672,441	09/30/97	AOKi et al.				
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Date Considered

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SK	AA	Des. 362,424	09/19/1995	Sumita et al.			•		
SK	AB	Des. 417,861	12/21/1999	Maeyama					
SK	AC	Des. 425,479	05/23/2000	Melnicoff					
SK	AD	D473,186 S	04/15/2003	Grosfeld et al.					
SK	AE	D515,499 S	02/21/2006	Matsuda et al.					
SK	AF	5,415,947	05/16/1995	Mitsui et al.					
SK	AG	5,510,205	04/23/1996	Ozer	 				
SK	AH	6,521,370 B1	02/18/2003	Takeshita et al.			· · · · · ·		
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	AB	Dec. 417,861	12/21/1999	Maeyama	<u> </u>		
	AC	Des. 425,479	05/23/2000	Melnicoff			
'	AD	D473,186 S	04/15/2003	Grosfeld et al.			
	AE	D515,499 S	02/21/2006	Matsuda eral.			
	AF	5,415,947	05/16/1995	Mitsui et al.			
	AG	5,510,205	04/23/1996	Ozer			
	AH	0,52 1,370 B1	02/18/2003	Takeshita et al.			
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